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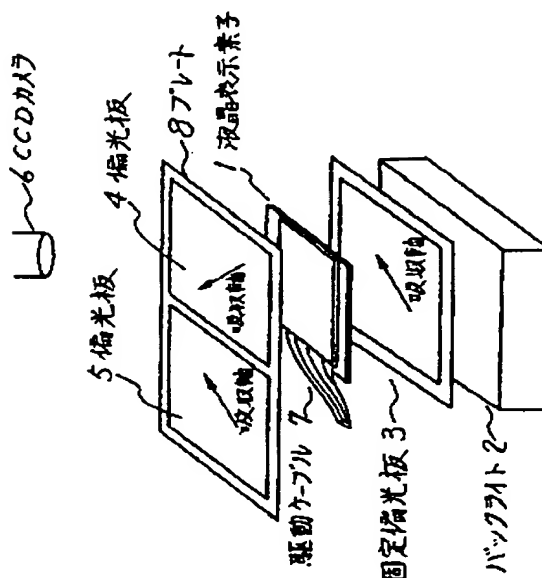
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TITLE : METHOD AND DEVICE FOR
INSPECTING LIQUID CRYSTAL
DISPLAY ELEMENT



ABSTRACT : PURPOSE: To enable inspection, especially, with high detection sensitivity by combining the directions of axis of absorption of polarizing plates, arranged on both the top and reverse surfaces of a liquid crystal display element, so that a defect position of the liquid crystal display element is a white dot.

CONSTITUTION: A fixed polarizing plate 3 is placed on a back light 2, and the liquid crystal display element 1 as a body to be inspected is put thereupon; and a polarizing plate 5 having its axis of absorption in parallel to that of the fixed polarizing plate 3 and a polarizing plate 4 which has its axis of absorption at right angles are arranged, side by side, thereupon and the plate 8 is movable. When a wire breaking mode defect is detected, the plate is moved to the right and the fixed polarizing plate 3 and polarizing plate 4 are combined to generate a normally white mode; when a short-circuit mode defect is detected, the plate is moved to the right and the fixed polarizing plate 3 and polarizing plate 4 are combined to generate a normal black mode. Consequently, the wire breaking mode defect and short-circuit mode defect can be detected with the same sensitivity and the accuracy of the defect inspection is improved.

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